

# **Notice of References Cited**

Application/Control No. <b>09/589,966</b>		Applicant(s)/Patent Under Reexam <b>Michael J. Demler</b>	
Examiner <b>Thai Phan</b>		Art Unit <b>2123</b>	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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B	5,535,223 ✓	7/1996	Horstmann et al.	371	27
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## **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages					
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